

J-PARC User ID Card Renewal for the new administrative year 2015

(H26[JFY2014]→H27[JFY2015])

24 February 2015

User ID Cards with number starting from H26- issued during Japanese fiscal year (JFY) 2015 (1st April 2014- 31st March 2015) will expire on "**31st March 2015**".

J-PARC users wishing to enter J-PARC site on and after 1st April must complete the following 2-steps procedures via User Support System (https://jrs.j-parc.jp/usjparc/ui/UI_00000E.do). If you have a registered Login ID (e-mail address) and password, login to the system to specify a purpose of your visit for 2015 JFY.

If you have a registered User ID (e-mail address) and password, login to the system. Select [Annual renewal of the registered experiment] or [Addition of new purpose].

[Annual renewal of the registered experiment]; for Users who have registered their experiment (Hadron, Neutrino, Neutron S type or Muon MS type) in 2014 JFY.

[Addition of new purpose]; for Users who add the new purpose or forgot to do annual renewal by 30th of April

Both [Annual renewal of the registered experiment] and [Addition of new purpose] are the procedures to register a purpose of your visit for JFY 2015. Some optional entries are omitted when you select [Annual renewal of the registered experiment].

If you work on multiple projects/experiments, you must do the procedure separately for each project.

New User

[New User Registration]

Those who wish to visit J-PARC for the first time need to be registered to User Support System.

2

Please submit “Application form to visit J-PARC” and “VISIT PROPOSAL (J-PARC)” via the system.

3

New User ID Card for JFY2015 will be issued.
Safety training is required on the first day of visit for all users.

<For reference>

New User Registration, Adding new experiment

: http://j-parc.jp/uo/page_eng/top/login.html

http://j-parc.jp/uo/page_eng/top/purpose.html

Application to visit J-PARC: http://is.j-parc.jp/uo/page_eng/exp/visit_ap.html

J-PARC Center Users Office

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